

32ND ASEMEP TECHNICAL SYMPOSIUM (ANTS)

"Cultivating the Power of Human-Machine Collaboration: Enhancing Creativity, Inspiring Innovation, and Paving the Way for the Next Industrial Revolution through Augmented Interactions"

October 26, 2023, 1:00 PM – 4:30 PM | World Trade Center, Metro Manila, Pasay City

PSECE 2023 Convention, DAY 2 (Thursday)
 Afternoon Breakout Session (39 Presentations + 1 Sponsor)

Category	Assembly Manufacturing	Assembly Manufacturing, FA/REL & Support Systems	Product & Quality Systems	Test Manufacturing & Quality Systems
Meeting Room	Track 1 (2F – Luna)	Track 2 (2F – Hidalgo)	Track 3 (2F – Amorsolo)	Track 4 (2F – Joya)
Moderators	Procy Aranda & Raynell Inojosa, PhD	Reggie Reyes & Ronel Dipalac, Evelyn Raguindin & Sandra Chu	Jimmy Apolinar & Laura May Clemente, Bernie Redoña, PhD & Ronald Hilaria	John Herber, PhD & Ruth Jacob
1:00 - 1:20 PM	[1] EMBRACING EVOLUTION: PHOTORESIST STRIPPING 2.0	[11] WIRELESS DETECTION OF ELECTROSTATIC DISCHARGE (ESD) EVENT THROUGH ELECTROMAGNETIC INTERFERENCE (EMI)	[1] ADDRESSING CRITICAL WIREBOND LOOP CHALLENGES ON AUTOMOTIVE MEMS DEVICE WITH STACKED-DICE CONFIGURATION	[1] TESTER EFFICIENCY IMPROVEMENT THROUGH REAL TIME IN-HOUSE STATISTICAL PROCESS CONTROL FOR RF FINAL TEST
	Texas Instruments Philippines, Inc. - Clark	P. IMES Corporation	STMicroelectronics, Inc.	Ampleon Philippines Inc.
	Assembly Manufacturing	Assembly Manufacturing	Product	Test Manufacturing
	Ma. Koselle L. Laxamana	. Elmer Soriao	Behra E. Bamba	Shiela Marie M. Ocampo
	Rafael Jose Guevara	-	Frederick Ray I. Gomez	Aristeo L. Dela Fuente
	-	-	-	Patrick Angelo S. Carreon
1:20 - 1:40 PM	[2] AUGMENTING CAPABILITY OF BOTTLENECK PROCESS AT CCU BACK-END ASSEMBLY	[12] REDUCTION OF PROCESS CYCLE TIME THROUGH THE INNOVATION OF MANUAL OR SEMI-AUTO JIGS & FIXTURES: D.I.A.D.O.I. BASED APPROACH	[2] DEEP-DIVE INVESTIGATION ON PAD DISCOLORATION ISSUE IN OPTICAL SENSING DEVICES	[2] QC FAILURE ELIMINATION: PREDICTING CURRENT SENSE TEST FAILURES THROUGH LINEAR REGRESSION
	Continental Electronics Technologies Phils. Inc.	P. IMES Corporation	STMicroelectronics, Inc.	onsemi Carmona
	Assembly Manufacturing	Assembly Manufacturing	Product	Test Manufacturing
	Precious O. Andales	Leonardo Z. Sarmiento	Rhodora D. Yu	Christine B. Baterbonia
	Mario O. Borja Jr.	Carla D. Aday	Jesse L. Jagape	Jhon V. Evangelista
-	-	Emiliana D. Antonio	Allan G. Seto Lam	

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1:40 – 2:00 PM	[3] ADAS MULTI-FUNCTION LIDAR SCRAP ELIMINATION	[13] WAFER SAW PROCESS IMPROVEMENT THROUGH LASER GROOVE KERF CHECK OPTIMIZATION	[3] OPTIMAL DESIGN OF SILICON CARBIDE MOSFET HALF BRIDGE POWER MODULE FOR 200A CURRENT RATING BASED ON ELECTROTHERMAL SIMULATION	[3] IMPROVING CONTACT RELIABILITY THRU RELIABILITY CENTERED MAINTENANCE APPROACH: A COST-EFFICIENT WAY OF CONTACT FINGER CONSUMPTION
	<i>Continental Electronics Technologies Phils. Inc.</i>	<i>STMicroelectronics, Inc.</i>	<i>Integrated Micro-Electronics, Inc.</i>	<i>Nexperia Philippines, Inc.</i>
	<i>Assembly Manufacturing</i>	<i>Assembly Manufacturing</i>	<i>Product</i>	<i>Test Manufacturing</i>
	Hazel Ongoco	Vianriz Marini B. Bautista	Genesis M. Cruz	Joebert T. Saballas
	Jan Paul Pangan	Jan Kurt A. Bulayungan	Christian Rocky D. Linatoc	Nicasio C. Badillo Jr.
	Jose Luis Paulo Pagala	Francis Noel A. de Erit	Gio Paolo C. Pascual	Reymart A. Ebea
2:00 - 2:20 PM	[4] ADAPTING LEAN AND ADVANCE MANUFACTURING TECHNOLOGY AT INERTIAL ASSEMBLY LINE	[14] ULTRA SHORT PULSE (USP) LASER GROOVING: A NEW SAWING TECHNIQUE TO ADDRESS DIE STRENGTH ISSUES IN THINNER PACKAGES	[1] ELIMINATION OF CONDUCTIVE DIE ATTACH FILM INTERFACIAL DELAMINATION DUE TO INTRINSIC HIGH ASPECT RATIO ULTRATHIN HIGH DIE BOW LEVEL	[4] TEST HANDLER JAM REDUCTION: AN IN-DEPTH ROOT-CAUSE ANALYSIS APPROACH ON UP/DOWN MOTOR ASSEMBLY FAILURE USING RELIABILITY CENTERED
	<i>Continental Electronics Technologies Phils. Inc.</i>	<i>STMicroelectronics, Inc.</i>	<i>Ampleon Philippines Inc.</i>	<i>Nexperia Philippines, Inc.</i>
	<i>Assembly Manufacturing</i>	<i>Assembly Manufacturing</i>	<i>Quality Systems</i>	<i>Test Manufacturing</i>
	Margie Tolentino	Aiza Marie Agudon	Marty Lorgino D. Pulutan	Benjarde Montoya
	Giovanni Arante	Jefferson Talledo	Olga S. Rivera	Christian James San Juan
	-	Boris Bouillard	-	Minotchka Yumol
2:20 - 2:40 PM	[5] SOT227 PRE-FORM/FINAL FORM POKA-YOKE FOR TOOL PARTS BREAKAGE PREVENTION	[1] VALIDATION OF PRESSURE SENSITIVE ADHESIVE AS ALTERNATIVE ACCELEROMETER ATTACHMENT ON ALUMINUM ALLOY JIG UNDER VIBRATION TEST WITH TEMPERATURE AND AXIS VARIATION	[2] DEVICE “T” ELECTRICAL YIELD IMPROVEMENT	[5] 3D SIMULATION SOFTWARE: EFFECTIVE TOOL ON REDESIGNING CLAMPING MECHANISM FOR DAMAGED STRIP ELIMINATION
	<i>Fastech Advanced Assembly Inc.</i>	<i>Integrated Micro-Electronics, Inc</i>	<i>ams OSRAM Group</i>	<i>STMicroelectronics, Inc.</i>
	<i>Assembly Manufacturing</i>	<i>FA/REL</i>	<i>Quality Systems</i>	<i>Test Manufacturing</i>
	Maureen T. Aliwalas	Gilbert Diwa	Joseph P. Panganiban	Eric G. Espino
	Primitivo L. Regencia Jr.	Harvey Naredo	Phillip Malaluan	Irish Jan T. Beltran
	Fernando G. Trogon	Jaime Ebero	-	Frielan Z. Mijares

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2:40 PM – 2:50 PM (10 MINS. AFTERNOON BREAK)				
2:50 – 3:10 PM	[6] EXCESSIVE FLASHING REDUCTION ON PLAD SINGLE-DIE/ BI-RECTIONAL DEVICES THRU STACK HEIGHT ANALYSIS	[2] HIGHLY ACCELERATED LIFE TEST AND ENVIRONMENTAL-3 ONGOING RELIABILITY TEST OPTIMIZATION	[3] NETWORK SYSTEMS SOLUTIONS INTEGRATION TO ELIMINATE MISSING OR INCOMPLETE SUPPLIER KEY DATA USED FOR COMPONENT TRACEABILITY	[8] ELIMINATION OF RBFA DISTURBED WIRE OCCURRENCE
	<i>Fastech Advanced Assembly Inc.</i>	<i>Knowles Electronics (Philippines) Corporation</i>	<i>STMicroelectronics, Inc.</i>	<i>onsemi Tarlac</i>
	<i>Assembly Manufacturing</i>	<i>FA/REL</i>	<i>Quality Systems</i>	<i>Quality Systems</i>
	Jason G. Sison	Gle-Ann Sumalingog	Elmar C. Magaling	Angel Christian, A., Cullado
	Primitivo L. Regencia Jr.	-	Judioz M. Manejero	Majhed, Quismundo
-	-	Mary Grace C. Tapia	-	
3:10 - 3:30 PM	[7] BRIDGE PICK TOOL MODIFICATION ON DACA MACHINES FOR TILTED CLIP AND CRACK DIE REJECT REDUCTION	[3] FRACTOGRAPHIC ANALYSIS OF DIE CRACK SIMULATED UNDER DIFFERENT FRACTURING CONDITIONS	[4] REDUCTION OF OVER REJECTION AT 5 SIDES VISION OF TEST & TAPE MACHINES	[9] LEADTIME IMPROVEMENT – BALANCED ARMATURE AGING REDUCTION
	<i>Nexperia Philippines, Inc.</i>	<i>STMicroelectronics, Inc.</i>	<i>onsemi Tarlac</i>	<i>Knowles Electronics (Philippines) Corporation</i>
	<i>Assembly Manufacturing</i>	<i>FA/REL</i>	<i>Quality Systems</i>	<i>Quality Systems</i>
	Harold Gutlay	Dexter Delos Santos	Jiannina Zocor B. Manalo	Meilin P. Torralba
	John Rhyan Llamas	Jefferson Talledo	-	-
-	-	-	-	
3:30 - 3:50 PM	[8] SUSTAINABLE DEVELOPMENT: A GUIDE TO PLATING COST EFFICIENCY	RISE: Pioneering the Future of Raman-SEM	[5] COMPARATIVE STUDY OF TWO SCANNING TECHNIQUES IN AUTOMATIC SIDE VISUAL INSPECTION OF WETTABLE FLANK QFN PACKAGES	[10] THREE-WAY TEST DETECTION ENHANCEMENT: A BREAKTHROUGH SOLUTION FOR SOLDER CRACK MARGINAL OPENS
	<i>Nexperia Philippines, Inc.</i>	Mr. Simon Fong Territory Sales Manager Oxford Instruments	<i>STMicroelectronics, Inc.</i>	<i>Texas Instruments Philippines, Inc. - Clark</i>
	<i>Assembly Manufacturing</i>		<i>Quality Systems</i>	<i>Quality Systems</i>
	Sebastian Novio		Rohn Kenneth L. Serapio	Abigail D. Malcon
	Leo Cada		Jerry T. Diwata	Villamor Jr. F. Zaparita
Kate Drew G. Heromiano	Ernesto T. Antilano Jr.		Mark D. Ramos	

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3:50 - 4:10 PM	[9] REDUCTION OF LOW VACUUM PRESSURE READING ON VACUUM PROCESSOR ASSEMBLY OF MATRIX PNP HEAD THROUGH 4M+1E ANALYSIS	[1] ELIMINATION OF EXTERNAL AND INTERNAL AUDIT FINDINGS RELATED TO MISALIGNED DOCUMENTATION	[6] OVER REJECTION DOWNTIME REDUCTION THROUGH MAGNETIZED CLEANING BRUSH	[11] IMPROVED MOLD TOOL DESIGN ROBUSTNESS THROUGH THE DMAIC PROCESS
	<i>P. IMES Corporation</i>	<i>onsemi Carmona</i>	<i>STMicroelectronics, Inc.</i>	<i>Nexperia Philippines, Inc.</i>
	<i>Assembly Manufacturing</i>	<i>Support Systems</i>	<i>Quality Systems</i>	<i>Quality Systems</i>
	Darwin B. Alcantara	Maria Erika Jane Gabriel	Frielan Z. Mijares	Walfredo Z. Peña
	Leonardo Z. Sarmiento	Michael James Domingo	Irish Jan T. Beltran	Arnel S. Berlon
-	-	Eric G. Espino	Erikson J. Mapote	
4:10 – 4:30 PM	[10] ELIMINATING SHORT CIRCUIT ON PLC SIGNALS THROUGH THE USE OF WIRE JUMPER FOR FAVI MACHINES	[2] AUTOMOLD CELL CONTROLLER: AUTOMATION OF MOLD MACHINES TO REDUCE QUALITY ISSUES	[7] TESTING PROCESS ROBUSTNESS: ELIMINATION OF POTENTIAL MIXING CUSTOMER COMPLAIN THROUGH ERROR PROOFING METHODOLOGY	[12] REDUCTION OF STRAY WIRE RBFA INCIDENT AT WIRE BOND
	<i>P. IMES Corporation</i>	<i>Allegro Microsystems Phils., Inc.</i>	<i>STMicroelectronics, Inc.</i>	<i>onsemi Tarlac</i>
	<i>Assembly Manufacturing</i>	<i>Support Systems</i>	<i>Quality Systems</i>	<i>Quality Systems</i>
	Pauline Joy R. Sayo	Abigail SarahKatrize M. Cruz	Frielan Z. Mijares	Majhed Quismundo
	Roldan Dominic S. Fronda	Rachelle Ann H. Lavarez	Irish Jan T. Beltran	Angel Christian A. Cullado
-	Chrisna C. Malabanan	Eric G. Espino	-	
4:30 PM – END OF ANTS DAY 1				